

**Photometry of Bright Regions on Mars: ISM Results.** Laurel Kirkland<sup>1</sup>, Allan Treiman<sup>1</sup>, and Scott Murchie<sup>2</sup>.<sup>1</sup>Lunar and Planetary Institute, Houston, TX; <sup>2</sup>Applied Physics Laboratory, Laurel, MD.

**Introduction.** Compositional interpretations of reflection spectra depend on changes in spectral band positions, albedo, and continuum slope. Spectra of bright regions on Mars (0.77-3.14 $\mu$ m) show that surface effects cause the measured reflectance to decrease as incidence, emission or phase angle increases. Aerosols make the continuum slope more negative and shift band centers to a longer wavelength with increasing emission angle (Fig.1). To normalize the data to a common viewing geometry, first the reflectance is corrected for phase angle and opposition effects, then a Minnaert function corrects for varying incidence and emission angles, and finally the increase in reflectance with emission angle caused by aerosols is subtracted from the spectra. The result allows spectra measured at different viewing geometries to be more accurately compared.

**Data used.** The Phobos-2 ISM data used cover 0.77-3.14 $\mu$ m in 64 channels with a spatial resolution of  $\sim 25 \times 25 \text{ km}^2$  or  $5 \times 5 \text{ km}^2$ . The phase angles range from  $\sim 1$ -20 degrees, and the incidence and emission angles from  $\sim 1$ -65 degrees. Each of the 9 low resolution images has 24 scans by approximately 100 lines, and the two high resolution images have 8 scans by about 285 lines. Each line runs approximately west-east, and is taken at a constant phase angle. Thus each image has 24 or 8 scans each taken at a constant phase angle, but with varying incidence and emission angles.

**Phase angle correction.** The correction for varying phase angle (pha) uses an empirical relation consistent with Thorpe's opposition curve [1] from Viking red images. The first step in deriving this curve uses the Minnaert function to calculate for each pha the apparent reflectance  $R_o$  where  $\mu = \mu_o = 0$ . To do this, for each scan covering smooth, bright areas, a Minnaert plot (Fig.2) is made using  $y = \text{Log}[R \times \mu]$  and  $x = \text{Log}[\mu \times \mu_o]$ , where  $\mu = \text{Cos}[\text{incidence angle}]$ ;  $\mu_o = \text{Cos}[\text{emission angle}]$ ; and  $R = \text{reflectance at } 1\mu\text{m}$ . To ensure that only areas with similar photometric properties are included, areas that do not plot cleanly on the Minnaert plot are not used. This causes isolated bright or dark patches to be excluded. A line fit to the Minnaert plot gives  $R_o = \text{Exp}[y - \text{intercept}]$  (Fig.2). This method is used for each scan that has sufficient homogenous, bright material to get a good result. These  $R_o$  values are plotted vs. phase angle, and to these data a fit of the form  $A + B \times \text{pha} + C \times \text{Exp}[-\text{pha}]$  is made (Fig.3). Dividing the reflectance by this curve corrects for phase angle effects, including

the opposition surge, but does not corrected for varying  $\mu_o$  or  $\mu$ :  $R_p = (R \times \text{offset}) / (A + B \times \text{pha} + C \times \text{Exp}[-\text{pha}])$

=phase corrected reflectance

where  $R = \text{ISM reflectance}$ ,

$A = 0.371$ ;  $B = -0.00185$ ;  $C = 0.0725$

$\text{offset} = A + B \times 20\text{deg} + C \times \text{Exp}[-20\text{deg}]$  to

normalize the correction to  $\text{pha} = 20\text{deg}$

**Incidence and emission angle correction.** To correct for varying  $\mu_o$  and  $\mu$ , we use a Minnaert function with  $k$  chosen to correct for the effects of the surface alone, and thus it does not correct the effects of aerosols. Reflective aerosols increase the apparent reflectance of the surface with emission angle, which decreases the Minnaert slope (Fig.2), and thus decreases the Minnaert  $k$  value [2]. The  $k$  values have a minimum at short wavelengths, and converge toward  $k = 0.87$  at approximately  $2.5\mu\text{m}$  (Fig.4). Therefore, we make a Minnaert correction using  $k = 0.87$ :

$$R_{pm} = R_p \times \mu / (\mu_o \times \mu)^{0.87}$$

where  $R_{pm}$  = phase and Minnaert corrected reflectance.

**Aerosol correction.** Two of the images cover very homogeneous areas and also have a large range of emission angles ( $\sim 5$ -60deg), which permits the effects of aerosols to be isolated. Within these two images, scans with the most homogenous mineralogy were chosen based on ratio plots of spectra across the image which have the least variation. For these scans, plots of  $R_{pm}$  vs.  $\mu$  show a linear relationship (Fig. 5), so the slope of a line fit to this plot gives the increase in reflectance with emission angle due to aerosols, the aerosol slope  $dR_{pm}/d\mu$ . To remove the aerosol contribution for a given spectrum, the aerosol slope at each wavelength is scaled by the emission angle, and this is added to the spectrum:

$$R_{pma} = R_{pm} + \text{slope} \times \mu, \text{ where } R_{pma} = \text{phase,}$$

Minnaert, and aerosol corrected reflectance.

The slope is generally negative, and the strength of the slope varies with location, but the correction to the entire data set uses the weaker slope to prevent introducing artifacts from overcorrecting.

**Results.** These photometric corrections bring the spectra into much better agreement within each image (Fig.6), and also improve the match of spectra taken from two different images which viewed the same location on Mars at different viewing angles. With these photometric corrections, it will be possible to derive firm conclusions about the mineralogy of the surface, regardless of viewing geometry.

**References.** [1] Thorpe, *Icarus* 49, 398, 1982. [2] Drossart et al., *Ann. Geophys.* 9, 754, 1991.

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